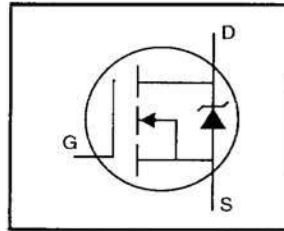


# IRL640PbF

## HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Logic-Level Gate Drive
- RDS(on) Specified at VGS=4V & 5V
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Lead-Free

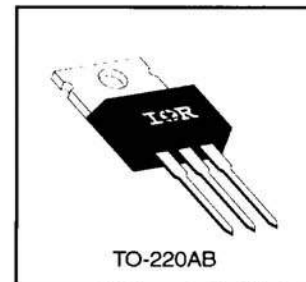


$V_{DSS} = 200V$   
 $R_{DS(on)} = 0.18\Omega$   
 $I_D = 17A$

### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.




### Absolute Maximum Ratings

Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	17	A
$I_D @ T_C = 100^\circ C$	11	
$I_{DM}$	68	
$P_D @ T_C = 25^\circ C$	125	W
	1.0	W/°C
$V_{GS}$	±10	V
$E_{AS}$	580	mJ
$I_{AR}$	10	A
$E_{AR}$	13	mJ
dv/dt	5.0	V/ns
$T_J$	-55 to +150	°C
$T_{STG}$		
	300 (1.6mm from case)	
	10 lbf•in (1.1 N•m)	


### Thermal Resistance

Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	—	—	1.0	°C/W
$R_{\theta CS}$	—	0.50	—	
$R_{\theta JA}$	—	—	62	

### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	200	—	—	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	0.27	—	V/°C	Reference to 25°C, I <sub>D</sub> =1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	0.18	Ω	V <sub>GS</sub> =5.0V, I <sub>D</sub> =10A ④
		—	—	0.27		V <sub>GS</sub> =4.0V, I <sub>D</sub> =8.5A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0	—	2.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
g <sub>fs</sub>	Forward Transconductance	16	—	—	S	V <sub>DS</sub> =50V, I <sub>D</sub> =10A ④
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	25	μA	V <sub>DS</sub> =200V, V <sub>GS</sub> =0V
		—	—	250		V <sub>DS</sub> =160V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> =10V
	Gate-to-Source Reverse Leakage	—	—	-100		V <sub>GS</sub> =-10V
Q <sub>g</sub>	Total Gate Charge	—	—	66	nC	I <sub>D</sub> =17A
Q <sub>gs</sub>	Gate-to-Source Charge	—	—	9.0		V <sub>DS</sub> =160V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	—	—	38		V <sub>GS</sub> =5.0V See Fig. 6 and 13 ④
t <sub>d(on)</sub>	Turn-On Delay Time	—	8.0	—	ns	V <sub>DD</sub> =100V
t <sub>r</sub>	Rise Time	—	83	—		I <sub>D</sub> =17A
t <sub>d(off)</sub>	Turn-Off Delay Time	—	44	—		R <sub>G</sub> =4.6Ω
t <sub>f</sub>	Fall Time	—	52	—		R <sub>D</sub> =5.7Ω See Figure 10 ④
L <sub>D</sub>	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6 mm (0.25in.) from package and center of die contact 
L <sub>S</sub>	Internal Source Inductance	—	7.5	—		
C <sub>iss</sub>	Input Capacitance	—	1800	—	pF	V <sub>GS</sub> =0V
C <sub>oss</sub>	Output Capacitance	—	400	—		V <sub>DS</sub> =25V
C <sub>rss</sub>	Reverse Transfer Capacitance	—	120	—		f=1.0MHz See Figure 5

### Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	17	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	68		
V <sub>SD</sub>	Diode Forward Voltage	—	—	2.0	V	T <sub>J</sub> =25°C, I <sub>S</sub> =17A, V <sub>GS</sub> =0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	310	470	ns	T <sub>J</sub> =25°C, I <sub>F</sub> =17A
Q <sub>rr</sub>	Reverse Recovery Charge	—	3.2	4.8	μC	di/dt=100A/μs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

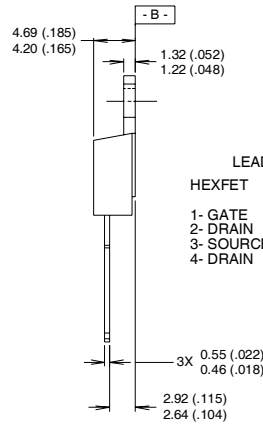
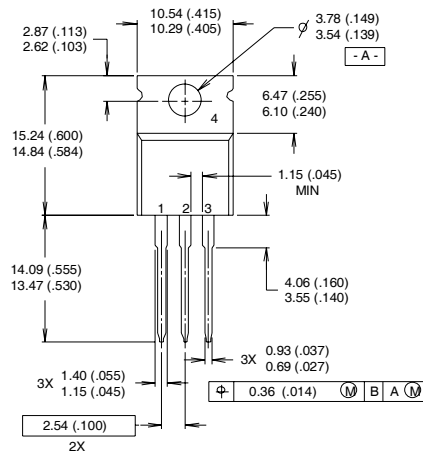
#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ② V<sub>DD</sub>=50V, starting T<sub>J</sub>=25°C, L=3.0mH R<sub>G</sub>=25Ω, I<sub>AS</sub>=17A (See Figure 12)
- ③ I<sub>SD</sub>≤17A, di/dt≤150A/μs, V<sub>DD</sub>≤V<sub>(BR)DSS</sub>, T<sub>J</sub>≤150°C
- ④ Pulse width ≤ 300 μs; duty cycle ≤2%.

# IRL640PbF

## TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



LEAD ASSIGNMENTS

HEXFET	IGBTs, CoPACK
1- GATE	1- GATE
2- DRAIN	2- COLLECTOR
3- SOURCE	3- EMITTER
4- DRAIN	4- COLLECTOR

NOTES:

- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
- 2 CONTROLLING DIMENSION : INCH

- 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

## TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010  
 LOT CODE 1789  
 ASSEMBLED ON WW 19, 1997  
 IN THE ASSEMBLY LINE "C"  
**Note:** "P" in assembly line  
 position indicates "Lead-Free"

